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(12) **United States Design Patent**
Ou et al.

(10) **Patent No.: US D481,962 S**
(45) **Date of Patent: ** Nov. 11, 2003**

(54) **TESTING MACHINE**

(75) Inventors: **Chun Nan Ou**, Shenzhen (CN); **GaLei Hu**, Shenzhen (CN); **Lin Yan**, Santa Clara, CA (US); **TaiPing Zhou**, Santa Clara (CN); **Yue Qing Zhao**, Shenzhen (CN)

(73) Assignee: **Hon Hai Precision Ind. Co., Ltd.**, Taipei Hsien (TW)

(**) Term: **14 Years**

(21) Appl. No.: **29/167,341**

(22) Filed: **Sep. 11, 2002**

(30) **Foreign Application Priority Data**

Aug. 30, 2002 (CN) 02 3 60995

(51) **LOC (7) Cl.** **10-04**
(52) **U.S. Cl.** **D10/75**
(58) **Field of Search** D10/75; 324/754, 324/761, 757, 540, 531, 546, 73.1, 158.1, 762, 537, 768, 755

(56) **References Cited**

U.S. PATENT DOCUMENTS

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Primary Examiner—Antoine Duval Davis
(74) *Attorney, Agent, or Firm*—Wei Te Chung

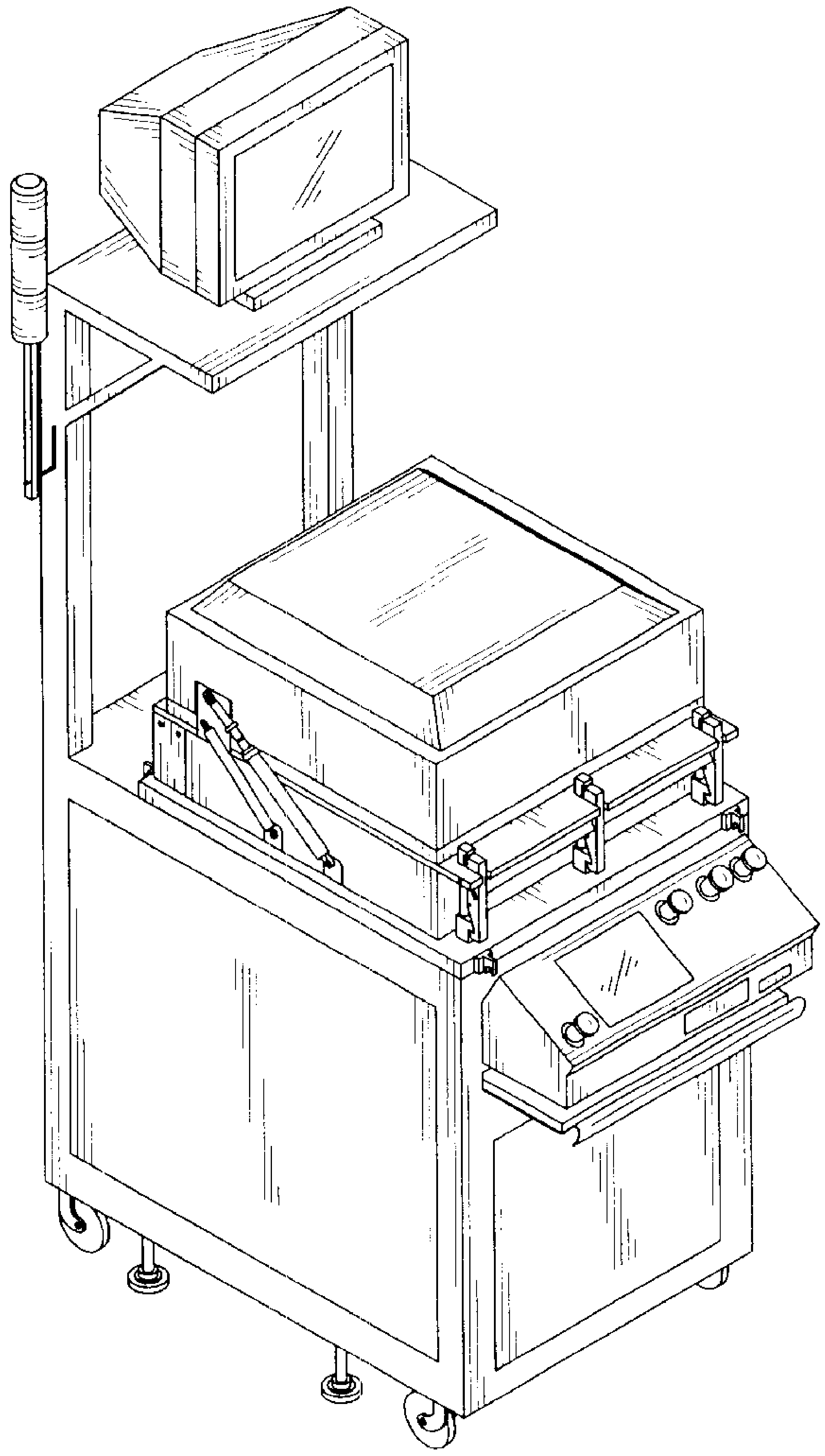
(57) **CLAIM**

The ornamental design for a testing machine, as shown.

DESCRIPTION

FIG. **1** is a perspective view of a testing machine of our new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a top plan view thereof; and,
FIG. **7** is a bottom plan view thereof.

1 Claim, 6 Drawing Sheets



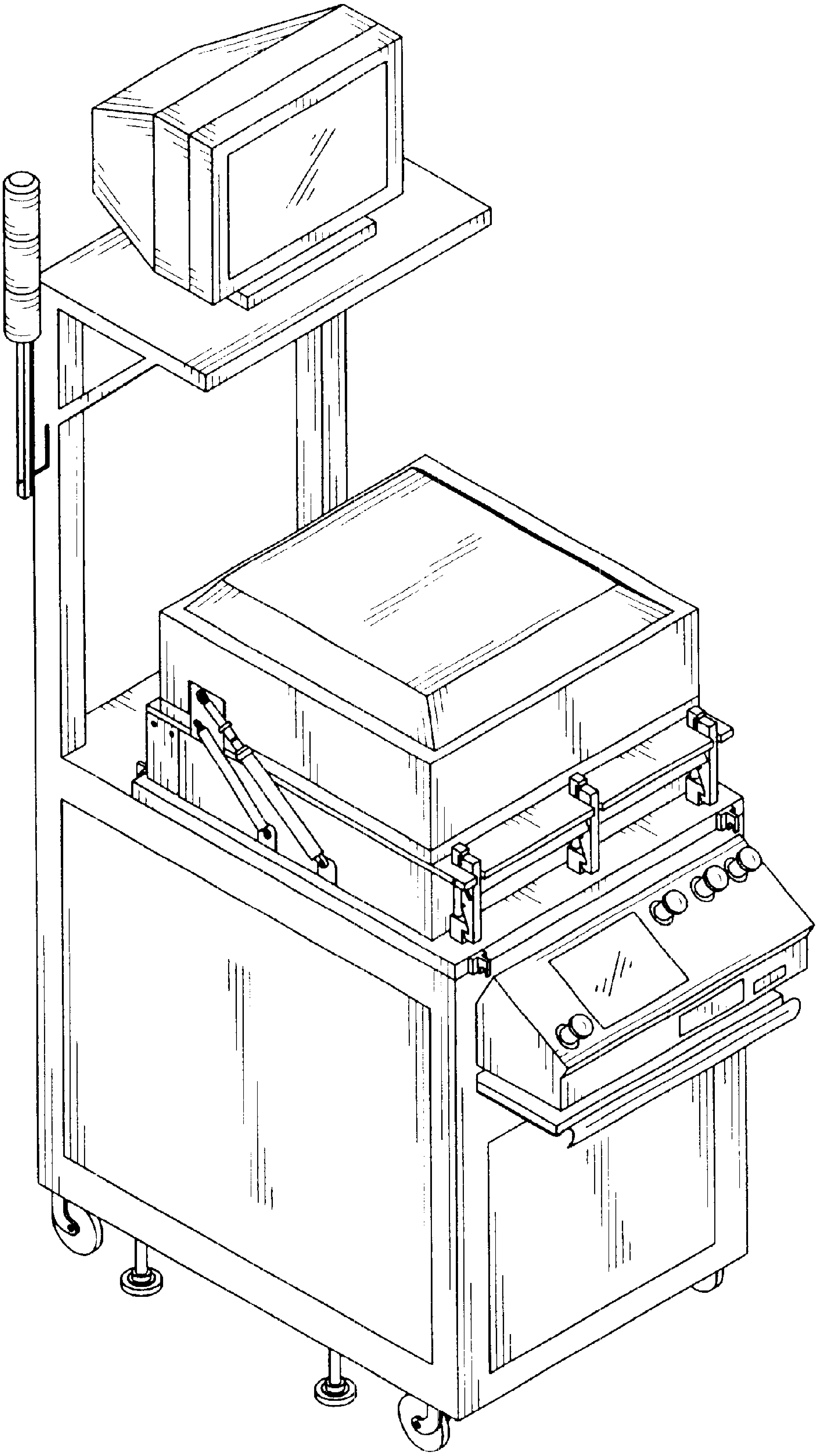


FIG. 1

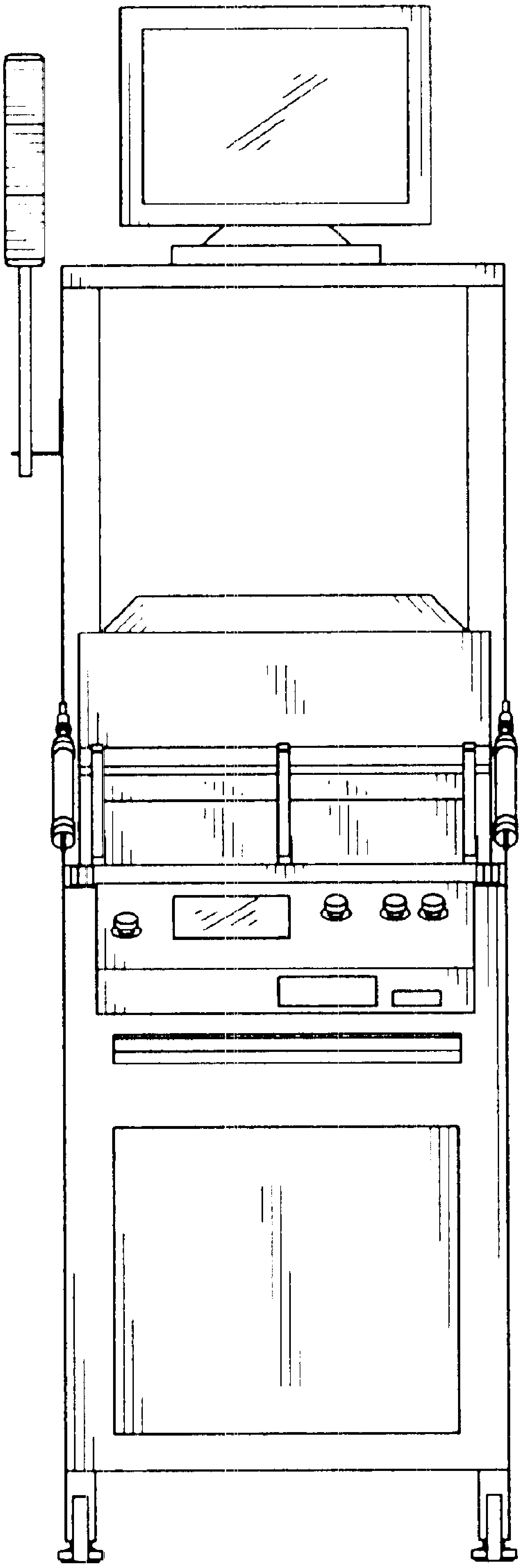


FIG. 2

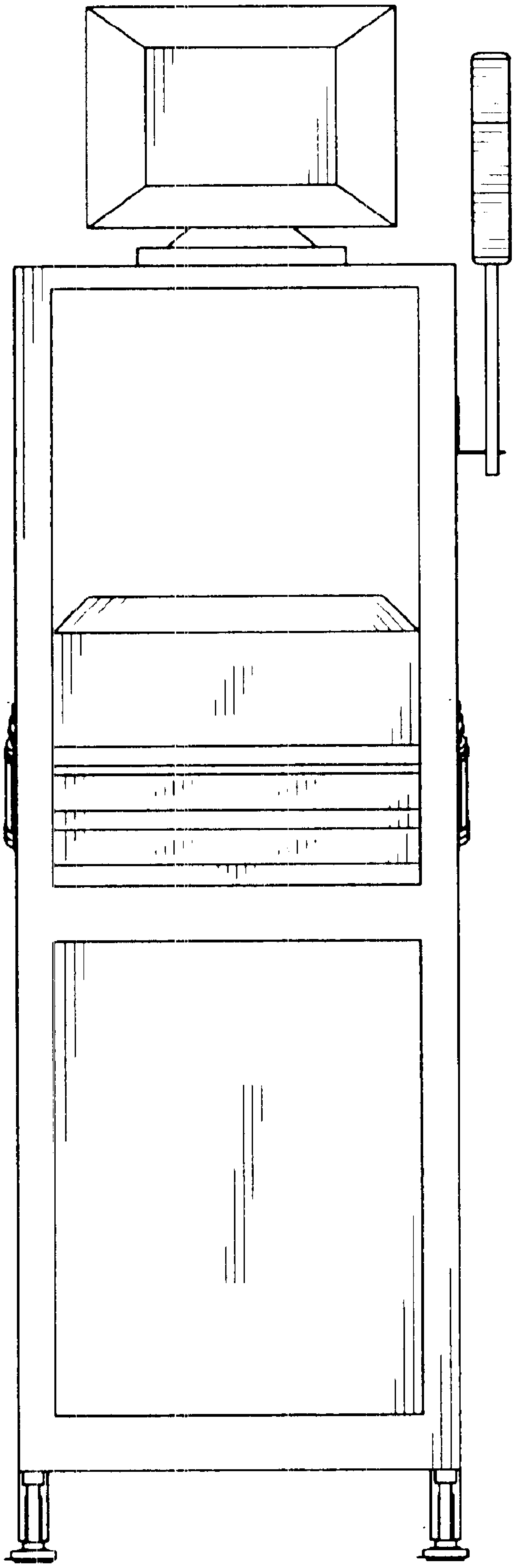


FIG. 3

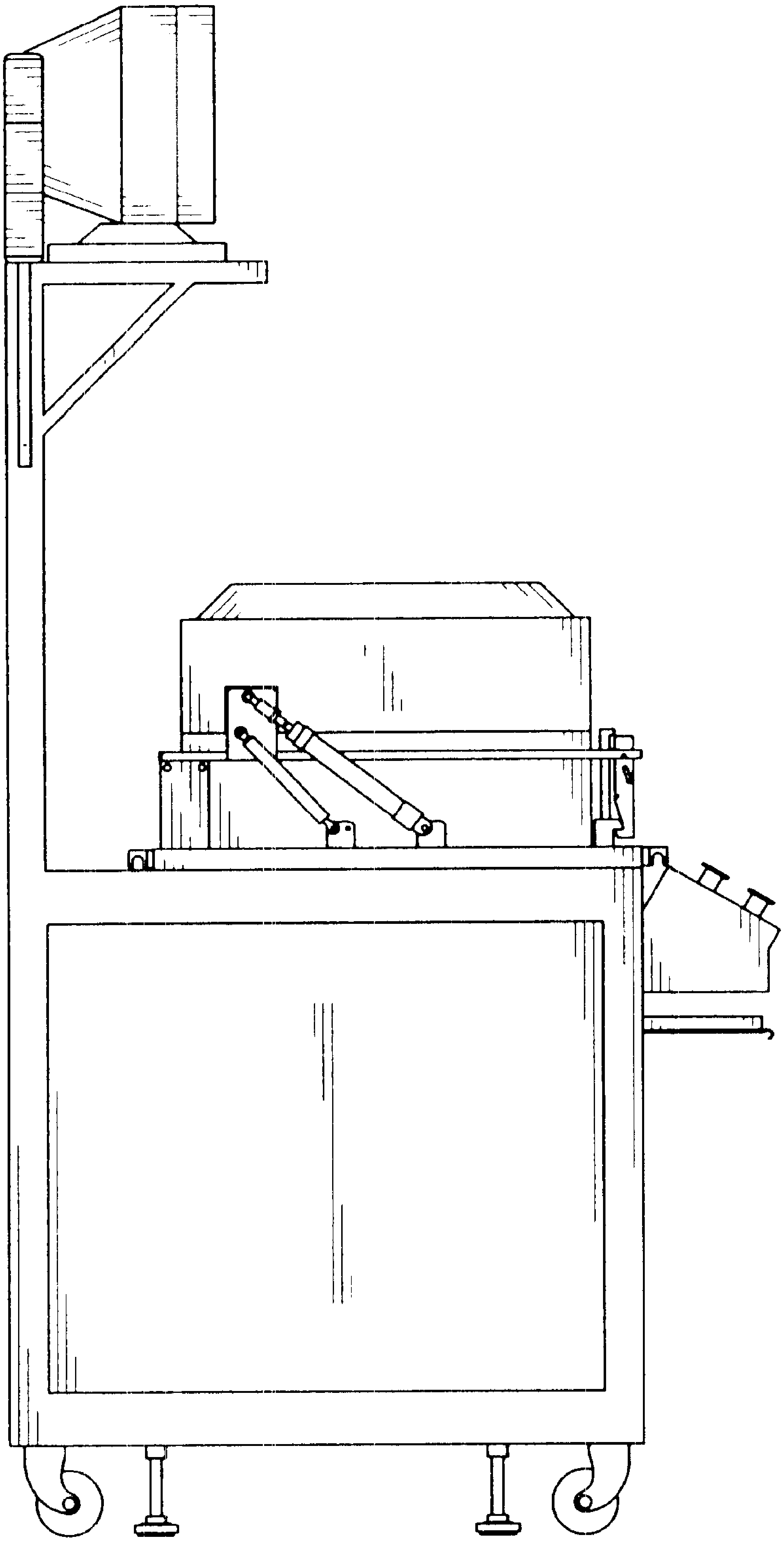


FIG. 4

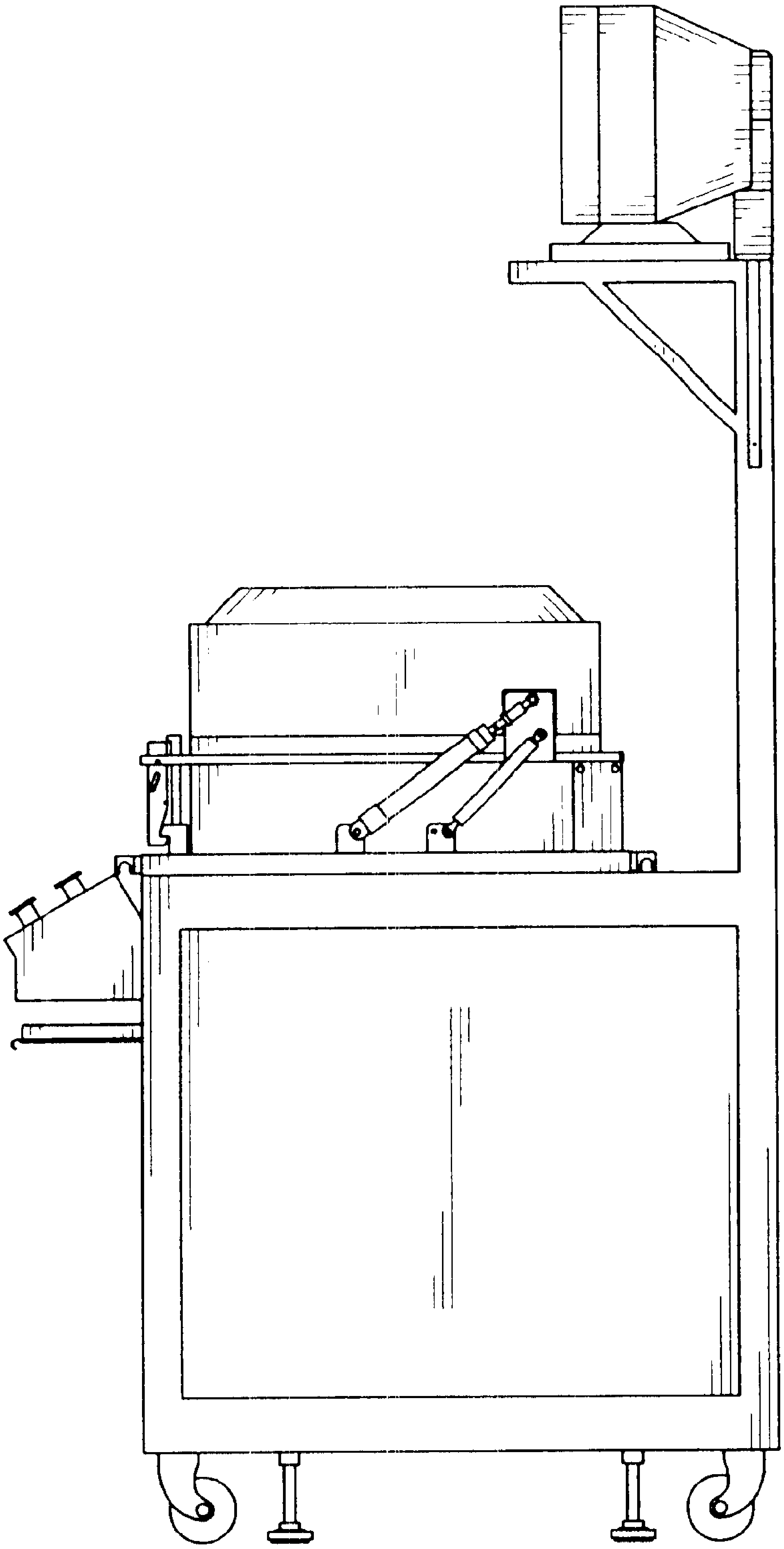


FIG. 5

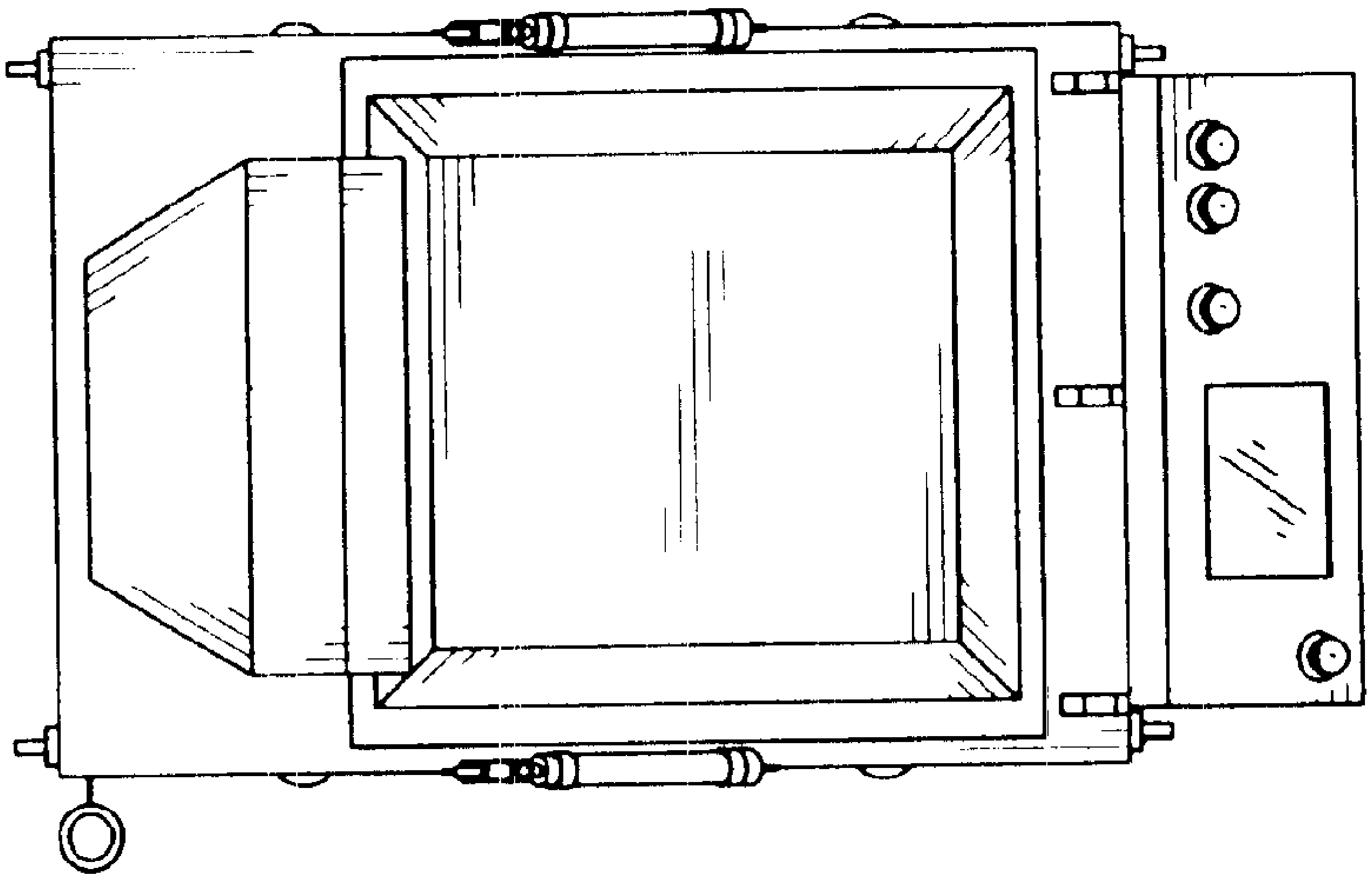


FIG. 6

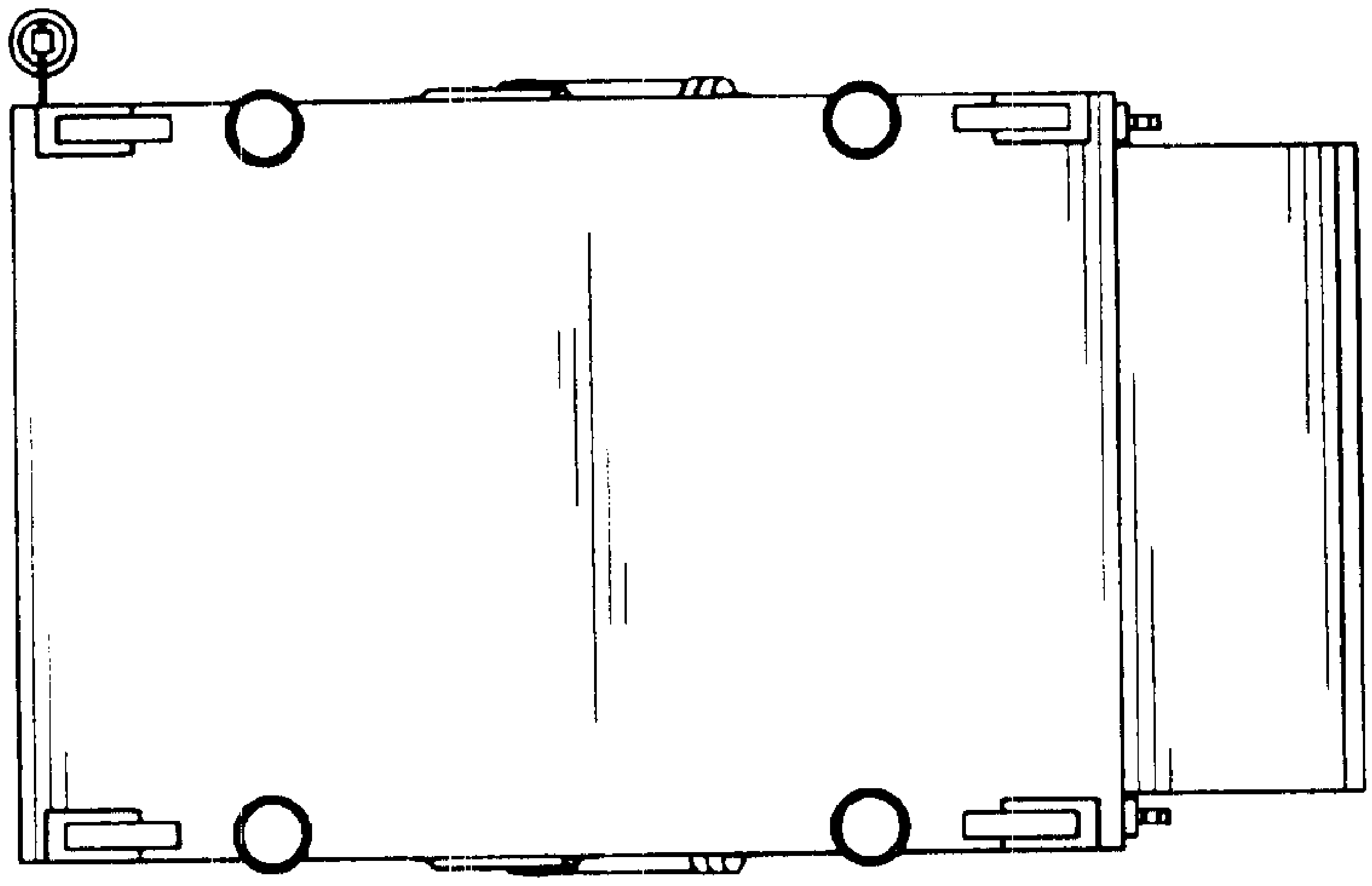


FIG. 7